

# Growth of Cobalt-containing Compounds for Back-End-of-Line Interconnects

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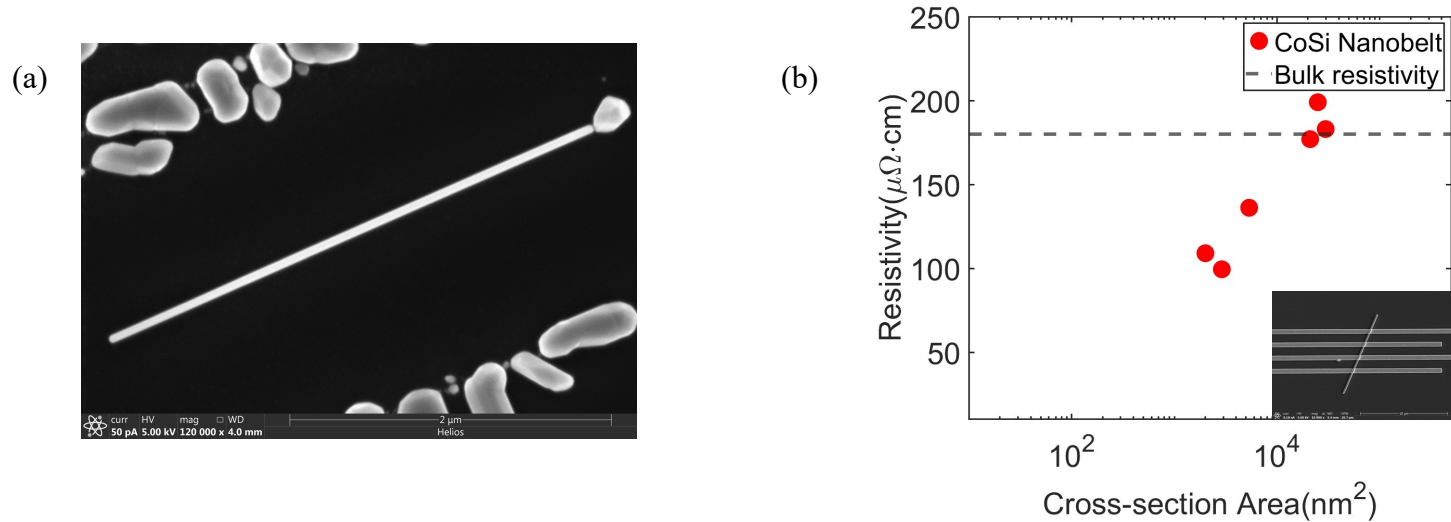


FIG. 1. (a) SEM image of as-grown CoSi nanobelt on HOPG substrate. (b) Dimension-dependent resistivity curve of CoSi nanobelts.

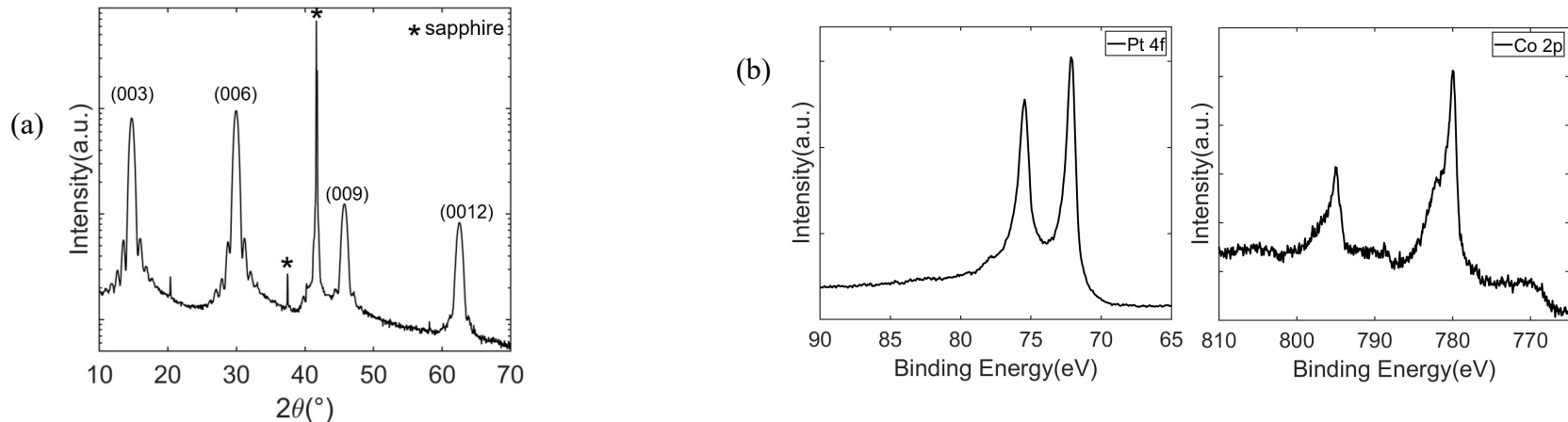


FIG. 2. (a)  $\theta - 2\theta$  XRD of PtCoO<sub>2</sub> thin film. (b) XPS spectra of Pt 4f and Co 2p for the PtCoO<sub>2</sub> thin film.